

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/524,098	<b>Applicant(s)/Patent under Reexamination</b> LEE ET AL.
	<b>Examiner</b> Quynh H. Nguyen	<b>Art Unit</b> 2614

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
379	207.08 207.16 211.03 211.04 374.03 375.01	9/18/07	QN
455	433 466	9/18/07	QN
Interference searched history printout		9/18/07	QN